



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#40/IDS
4/12/14
Sunken

Application Serial No. 09/559,903
Filing Date April 26, 2000
Inventor Zhiping Yin et al.
Assignee Micron Technology, Inc.
Group Art Unit 2815
Examiner Eckert II, George C.
Attorney's Docket No. MI22-1427
Title: Circuitry and Gate Stacks Encompassing a Semiconductive Substrate, a Metal
Silicide Layer and Inorganic Material Layer in Physical Contact with the Metal
Silicide Layer

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

To: Mail Stop RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

From: Jennifer J. Taylor, Ph.D. (Tel. 509-624-4276; Fax 509-838-3424)
Wells St. John P.S.
601 W. First Avenue, Suite 1300
Spokane, WA 99201-3828

Dear Sir:

The Examiner's attention is directed to the references which are listed on
the attached Form PTO-1449 and copies of which are attached.

Citation of these references is respectfully requested.

Respectfully submitted,

Dated:

March 12, 2004

By:

Jennifer J. Taylor
Jennifer J. Taylor, Ph.D.
Reg. No. 48,711

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1427		SERIAL NO. 09/559,903	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Zhiping Yin et al.			
				FILING DATE April 26, 2000		GROUP 2815	
U.S. PATENT DOCUMENTS							
*Examiner		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
AA		6,153,504	11-2000	Shields et al.			
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AM	07201716 A	08-1995	Japan			X
	AN	08046186 A	02-1996	Japan			X
	AO	10-163083	06-1998	Japan			X
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	A						
	R						
	AS						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							